

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>212812US2</b>		SERIAL NO. <b>09/930,202</b>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Takashi IPPOSHI, et al.</b>			
				FILING DATE <b>RCE Filed Herewith</b>		GROUP <b>2815</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
JN	AO	JP05090117	04/09/93	JAPAN W/ENGLISH ABSTRACT			X
	AP	JP01241854	09/26/89	JAPAN W/ENGLISH ABSTRACT			X
	AQ	JP56060061	05/23/81	JAPAN W/ENGLISH ABSTRACT			X
	AR	JP06005569	01/14/94	JAPAN W/ENGLISH ABSTRACT			X
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
JN	AW	Effect of <100> Channel Direction for High Performance SCE Immune pMOSFET with Less Than 0.15µm Gate Length, H. Sayama, et al.; International Electron Devices Meeting 1999; IEDM. Technical Digest, Washington, DC; Dec. 5-8, 1999; New York, NY; IEEE US; pp. 657-660.					
	AX	Smart Cut: A Promising New SOI Material Technology; Bruel, M. et al.; 1995 IEEE International SOI Conference Proceedings; Tuscon, Oct. 3-5, 1995; Proceedings of the Annual SOS/SOI Technology Conference. (From 1991 Proceedings of the International SOI Conference.) Silicon-on-Insulator Technology and Devices, New York, Oct. 3, 1995; pp. 178-179.					
	AY	High-Quality Epitaxial Layer Transfer (Eltran) by Bond and Etch-Back of Porous Si; Sato, et al.; 1995 IEEE International SOI Conference Proceedings. Tuscon, Oct. 3-5, 1995, Proceedings of the Annual SOS/SOI Technology Conference. (From 1991 Proceedings of the International SOI Conference.) Silicon-On-Insulator Technology and Devices, New York, Oct. 3, 1995, pp. 176-177.					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <b>JOSEPH NAVYEN</b>					Date Considered <b>6/29/04</b>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							